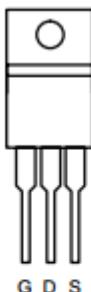


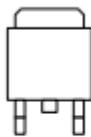
PRODUCT SUMMARY		
V _{(BR)DSS} (V)	r _{D(on)} (Ω)	I _D (A)
60	0.008	75 ^a

TO-220AB



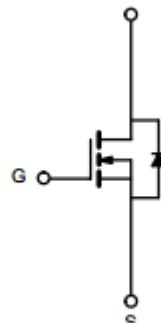
Top View
SUP75N06-08

TO-263



Top View
SUB75N06-08

D



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C UNLESS OTHERWISE NOTED)

Parameter	Symbol	Limit	Unit
Gate-Source Voltage	V _{GS}	± 20	V
Continuous Drain Current (T _J = 175°C)	T _C = 25°C	I _D	75 ^a
	T _C = 125°C		55
Pulsed Drain Current	I _{DM}	240	A
Avalanche Current	I _{AR}	60	
Repetitive Avalanche Energy ^b	E _{AR}	280	mJ
Power Dissipation	T _C = 25°C (TO-220AB and TO-263)	P _D	250 ^c
	T _A = 25°C (TO-263) ^d		3.7
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 175	°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Limit	Unit
Junction-to-Ambient	R _{thJA}	40	°C/W
Free Air (TO-220AB)		62.5	
Junction-to-Case	R _{thJC}	0.6	

Notes

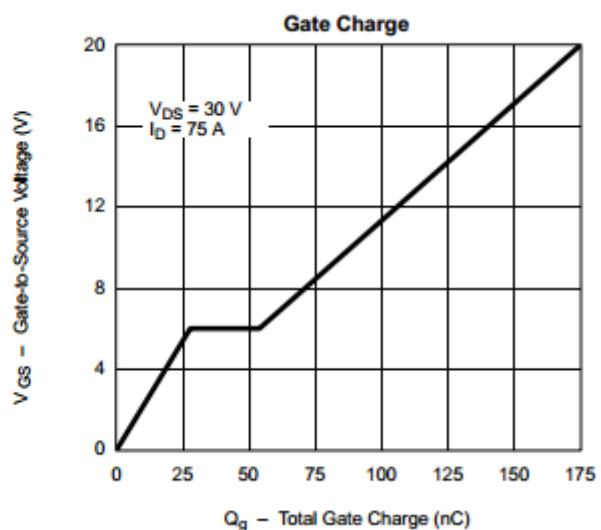
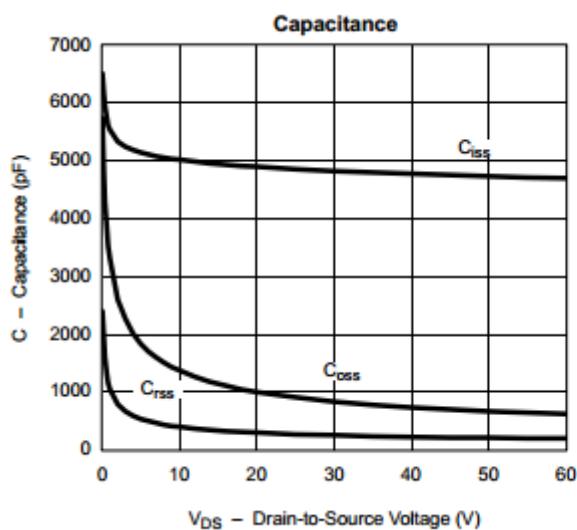
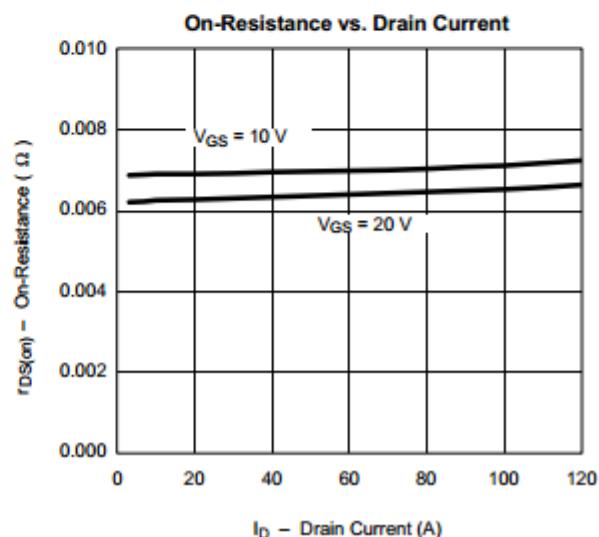
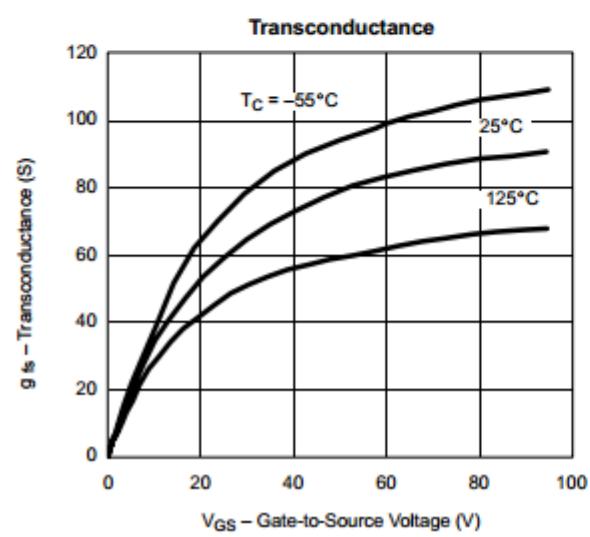
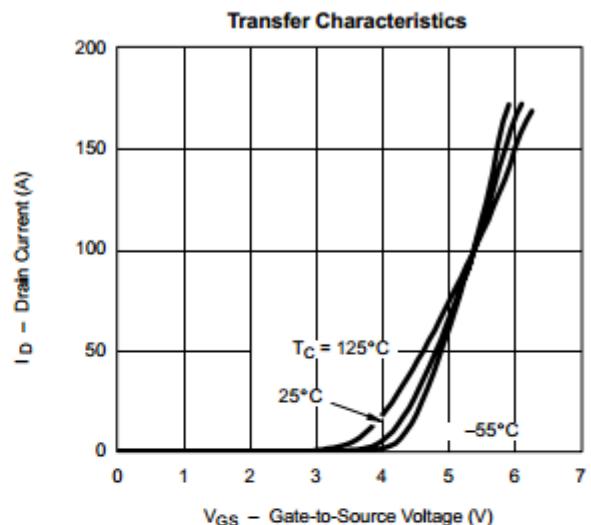
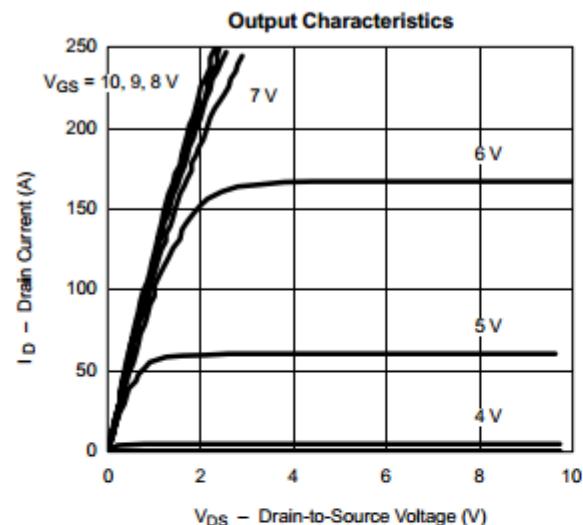
- a. Package limited.
- b. Duty cycle $\leq 1\%$.
- c. See SOA curve for voltage derating.
- d. When mounted on 1" square PCB (FR-4 material).

SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)						
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	3.0	4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			50	μA
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			150	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		0.007	0.008	
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125^\circ\text{C}$			0.012	Ω
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175^\circ\text{C}$			0.016	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$	30			S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		4800		
Output Capacitance	C_{oss}			910		pF
Reverse Transfer Capacitance	C_{rss}			270		
Total Gate Charge ^c	Q_g	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 75 \text{ A}$		85	120	
Gate-Source Charge ^c	Q_{gs}			28		nC
Gate-Drain Charge ^c	Q_{gd}			26		
Turn-On Delay Time ^c	$t_{d(on)}$	$V_{DD} = 30 \text{ V}, R_L = 0.47 \Omega$ $I_D = 75 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 2.5 \Omega$		20	40	
Rise Time ^c	t_r			95	200	
Turn-Off Delay Time ^c	$t_{d(off)}$			65	120	ns
Fall Time ^c	t_f			20	60	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)^b						
Continuous Current	I_S				75	
Pulsed Current	I_{SM}				240	A
Forward Voltage ^a	V_{SD}	$I_F = 75 \text{ A}, V_{GS} = 0 \text{ V}$		1.0	1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 75 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$		67	120	ns
Peak Reverse Recovery Current	$I_{RM(REC)}$			6	8	A
Reverse Recovery Charge	Q_{rr}			0.2	0.48	μC

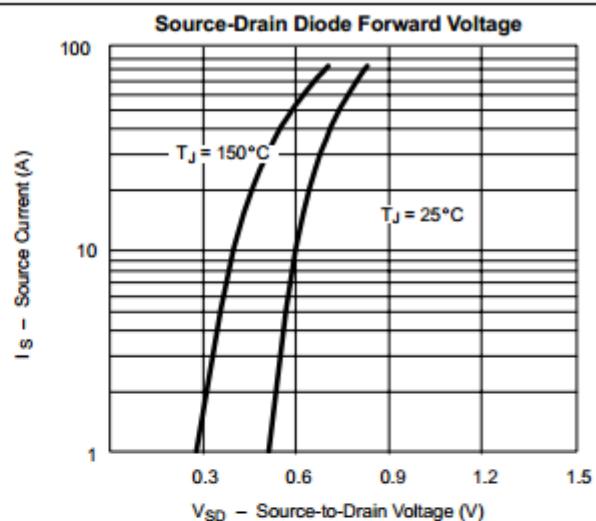
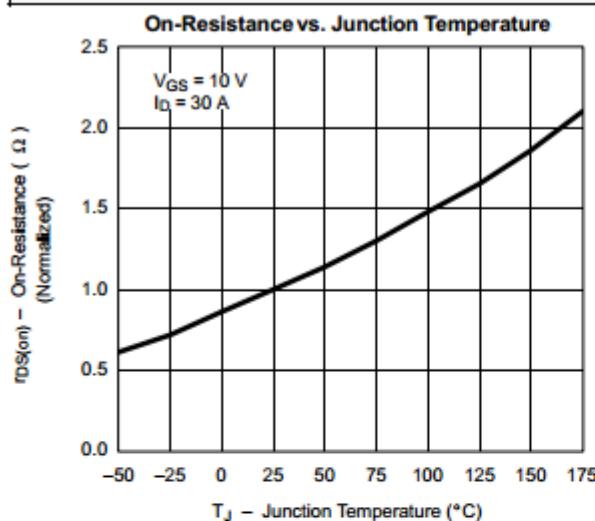
Notes

- a. Pulse test: pulse width $\leq 300 \mu\text{sec}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)



TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)



THERMAL RATINGS

